

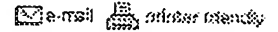
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L1	7870	((257/295,e27.048,e27.084,e27.104,e29.164,e29.272,e29.342,e29.343,e21.208,e21.663,e21.664) or (438/3) or (365/145) or (501/134)).CCLS.	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:22
L2	3744	1 and ferroelectric	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:22
L3	3317	2 and (@ad<"20030204" or @rlad<"20030204")	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:23
L4	2689	3 and capacitor	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:23
L5	2305	4 and electrode	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:23
L6	1820	3 and (ferroelectric same capacitor same electrode)	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:24
L7	352	6 and pzt and plzt	US-PGPUB; USPAT; EPO; JPO; IBM_TDB	OR	OFF	2005/06/25 09:24
L8	15	("20020015852" "20020153543" "5387459" "5656382" "5719417" "5850089" "5998236" "6090443" "6229166" "6258459" "6376090" "6385355" "6411017" "6511161" "6526833").PN. OR ("6841817").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 09:33

L9	59	("0476274" "2490547" "2622184" "2801322" "2925329" "3190262" "3404873" "3520416" "3549412" "3659402" "3823926" "3969449" "4036915" "4080926" "4288396" "4529427" "4833976" "4842893" "4847469" "4954371" "5034372" "5097800" "5110622" "5120703" "5139999" "5165960" "5204314" "5225561" "5248787" "5259995" "5280012" "5376409" "5536323" "5554866").PN. OR ("5998236").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 09:52
L10	78	("2695396" "2992929" "3529978" "3977887" "4144591" "4149301" "4244722" "4360896" "4503482" "4697222" "4792463" "4917810" "4918350" "4978646" "5046043" "5109771" "5122923" "5146299" "5369068").PN. OR ("5519234"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 10:55
L11	16	("5426075" "5434102" "5468679" "5519234" "5784310" "5824590" "5833745" "5902639").PN. OR ("6194227").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 11:02
L12	14	("5146299" "5478653" "5519234" "5576564" "5780886").PN. OR ("5989927"). URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 11:04
L13	29	("4786837" "5247189" "5519234" "5578867").PN. OR ("5736759").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 11:10
L14	16	("5736759" "5833745" "5994153" "6043526").PN. OR ("6153898").URPN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/06/25 11:14

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 Hang-Ting Lue; Chien-Jang Wu; Tseung-Yuen Tseng;
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 Veng Cheong Lo; Zhi Jiang Chen;
 Ultrasonics, Ferroelectrics and Frequency Control, IEEE Transactions on
 Volume 49, Issue 7, July 2002 Page(s):980 - 986
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- ☐ **4. Effect of interconnect layer on Pb(Zr,Ti)O₃ thin film capacitor degradation**
 Kobayashi, S.; Amanuma, K.; Hada, H.;
 Electron Device Letters, IEEE
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- ☐ **5. Quantitative determination of the dielectric constant of the interfacial layer in PZT ferroelectric capacitors**
 Bartic, A.T.; Wouters, D.J.; Jin Sing; Norga, G.; Bender, H.; Maes, H.E.;
 Applications of Ferroelectrics, 1998. ISAF 98. Proceedings of the Eleventh IEEE International Symposium on
 24-27 Aug. 1998 Page(s):73 - 76
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- ☐ **6. Effect of crystallisation on fatigue in sol-gel PZT ferroelectric capacitors with reactively sputtered RuO₂ electrode layers**
 Norga, G.J.; Wouters, D.J.; Bartic, A.; Fe, L.; Maes, H.E.;
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- ☐ **7. Pulsed laser deposition of metallic oxide thin films for microelectronic applications**
 Varela, M.; Trtik, V.; Guerrero, C.; Roldan, J.; Benitez, F.; Ferrater, C.; Sanchez, F.; Bibes, M.; Rubi, R.;

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